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### Details

Product Status	Active
Core Processor	HCS12
Core Size	16-Bit
Speed	16MHz
Connectivity	CANbus, EBI/EMI, SCI, SPI
Peripherals	POR, PWM, WDT
Number of I/O	60
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	2.35V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	80-QFP
Supplier Device Package	80-QFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s12c32vfue16

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



### Chapter 1 MC9S12C and MC9S12GC Device Overview (MC9S12C128)



The figure shows a useful map, which is not the map out of reset. After reset the map is: 0x0000–0x03FF: Register Space 0x0C00–0x0FFF: 1K RAM

The 16K flash array page 0x003F is also visible in the PPAGE window when PPAGE register contents are odd. Flash Erase Sector Size is 512 Bytes

### Figure 1-6. MC9S12GC16 User Configurable Memory Map



### **Detailed Register Map** 1.2.2

The detailed register map of the MC9S12C128 is listed in address order below.

0x0000-	0x000F	MEBI	Map 1 o	f 3 (HCS	512 Multi	iplexed I	External	Bus Inte	erface)	
Address	Name		Bit 7	Bit 6	Bit 5	Bit 4	Bit 3	Bit 2	Bit 1	Bit 0
0x0000	PORTA	Read: Write:	Bit 7	6	5	4	3	2	1	Bit 0
0x0001	PORTB	Read: Write:	Bit 7	6	5	4	3	2	1	Bit 0
0x0002	DDRA	Read: Write:	Bit 7	6	5	4	3	2	1	Bit 0
0x0003	DDRB	Read: Write:	Bit 7	6	5	4	3	2	1	Bit 0
0x0004	Reserved	Read: Write:	0	0	0	0	0	0	0	0
0x0005	Reserved	Read: Write:	0	0	0	0	0	0	0	0
0x0006	Reserved	Read: Write:	0	0	0	0	0	0	0	0
0x0007	Reserved	Read: Write:	0	0	0	0	0	0	0	0
0x0008	PORTE	Read: Write:	Bit 7	6	5	4	3	2	Bit 1	Bit 0
0x0009	DDRE	Read: Write:	Bit 7	6	5	4	3	Bit 2	0	0
0x000A	PEAR	Read: Write:	NOACCE	0	PIPOE	NECLK	LSTRE	RDWE	0	0
0x000B	MODE	Read: Write:	MODC	MODB	MODA	0	IVIS	0	EMK	EME
0x000C	PUCR	Read: Write:	PUPKE	0	0	PUPEE	0	0	PUPBE	PUPAE
0x000D	RDRIV	Read:	RDPK	0	0	RDPE	0	0	RDPB	RDPA
0x000E	EBICTL	Read:	0	0	0	0	0	0	0	ESTR
		Bead	0	0	0	0	0	0	0	0
0x000F	Reserved	Write:	•	Ű		U U	, ,	Ŭ	Ű	Ű



Chapter 2 Port Integration Module (PIM9C32) Block Description

## 2.3.2.6.3 Port AD Data Direction Register (DDRAD)

Module Base + 0x0032



Figure 2-42. Port AD Data Direction Register (DDRAD)

Read: Anytime.

Write: Anytime.

Table 2-34. DDRAD Field Descriptions

Field	Description			
7–0	Data Direction Port AD — This register configures port pins AD[7:0] as either input or output.			
DDRAD[7:0]	Associated pin is configured as input.			
	1 Associated pin is configured as output.			
	Note: Due to internal synchronization circuits, it can take up to 2 bus cycles until the correct value is read on			
	PTAD or PTIAD registers, when changing the DDRAD register.			

## 2.3.2.6.4 Port AD Reduced Drive Register (RDRAD)

Module Base + 0x0033



Figure 2-43. Port AD Reduced Drive Register (RDRAD)

Read: Anytime.

Write: Anytime.

### Table 2-35. RDRAD Field Descriptions

Field	Description
7–0 RDRAD[7:0]	<ul> <li>Reduced Drive Port AD — This register configures the drive strength of each port AD output pin as either full or reduced. If the port is used as input this bit is ignored.</li> <li>0 Full drive strength at output.</li> <li>1 Associated pin drives at about 1/3 of the full drive strength.</li> </ul>



### **Table 5-3. ITEST Field Descriptions**

Field	Description
7:0 INT[E:0]	<b>Interrupt TEST Bits</b> — These registers are used in special modes for testing the interrupt logic and priority independent of the system configuration. Each bit is used to force a specific interrupt vector by writing it to a logic 1 state. Bits are named INTE through INTO to indicate vectors 0xFFxE through 0xFFx0. These bits can be written only in special modes and only with the WRTINT bit set (logic 1) in the interrupt test control register (ITCR). In addition, I interrupts must be masked using the I bit in the CCR. In this state, the interrupt input lines to the interrupt sub-block will be disconnected and interrupt requests will be generated only by this register. These bits can also be read in special modes to view that an interrupt requested by a system block (such as a peripheral block) has reached the INT module.
	There is a test register implemented for every eight interrupts in the overall system. All of the test registers share the same address and are individually selected using the value stored in the ADR[3:0] bits of the interrupt test control register (ITCR).
	<b>Note:</b> When ADR[3:0] have the value of 0x000F, only bits 2:0 in the ITEST register will be accessible. That is, vectors higher than 0xFFF4 cannot be tested using the test registers and bits 7:3 will always read as a logic 0. If ADR[3:0] point to an unimplemented test register, writes will have no effect and reads will always return a logic 0 value.

## 5.3.2.3 Highest Priority I Interrupt (Optional)

Module Base + 0x001F

Starting address location affected by INITRG register setting.



### Figure 5-4. Highest Priority I Interrupt Register (HPRIO)

### Read: Anytime

Write: Only if I mask in CCR = 1

Table 5	5-4. HP	<b>RIO</b> Field	d Descri	ptions
---------	---------	------------------	----------	--------

Field	Description
7:1 PSEL[7:1]	<b>Highest Priority I Interrupt Select Bits</b> — The state of these bits determines which I-bit maskable interrupt will be promoted to highest priority (of the I-bit maskable interrupts). To promote an interrupt, the user writes the least significant byte of the associated interrupt vector address to this register. If an unimplemented vector address or a non I-bit masked vector address (value higher than 0x00F2) is written, IRQ (0xFFF2) will be the default highest priority interrupt.

## 5.4 Functional Description

The interrupt sub-block processes all exception requests made by the CPU. These exceptions include interrupt vector requests and reset vector requests. Each of these exception types and their overall priority level is discussed in the subsections below.



If a read command is issued but the data is not retrieved within 512 serial clock cycles, a soft-reset will occur causing the command to be disregarded. The data is not available for retrieval after the time-out has occurred. This is the expected behavior if the handshake protocol is not enabled. However, consider the behavior where the BDC is running in a frequency much greater than the CPU frequency. In this case, the command could time out before the data is ready to be retrieved. In order to allow the data to be retrieved even with a large clock frequency mismatch (between BDC and CPU) when the hardware handshake protocol is enabled, the time out between a read command and the data retrieval is disabled. Therefore, the host could wait for more then 512 serial clock cycles and continue to be able to retrieve the data from an issued read command. However, as soon as the handshake pulse (ACK pulse) is issued, the time-out feature is re-activated, meaning that the target will time out after 512 clock cycles. Therefore, the host needs to retrieve the data within a 512 serial clock cycles time frame after the ACK pulse had been issued. After that period, the read command is discarded and the data is no longer available for retrieval. Any falling edge of the BKGD pin after the time-out period is considered to be a new command or a SYNC request.

Note that whenever a partially issued command, or partially retrieved data, has occurred the time out in the serial communication is active. This means that if a time frame higher than 512 serial clock cycles is observed between two consecutive negative edges and the command being issued or data being retrieved is not complete, a soft-reset will occur causing the partially received command or data retrieved to be disregarded. The next falling edge of the BKGD pin, after a soft-reset has occurred, is considered by the target as the start of a new BDM command, or the start of a SYNC request pulse.

## 6.4.13 Operation in Wait Mode

The BDM cannot be used in wait mode if the system disables the clocks to the BDM.

There is a clearing mechanism associated with the WAIT instruction when the clocks to the BDM (CPU core platform) are disabled. As the clocks restart from wait mode, the BDM receives a soft reset (clearing any command in progress) and the ACK function will be disabled. This is a change from previous BDM modules.

## 6.4.14 Operation in Stop Mode

The BDM is completely shutdown in stop mode.

There is a clearing mechanism associated with the STOP instruction. STOP must be enabled and the part must go into stop mode for this to occur. As the clocks restart from stop mode, the BDM receives a soft reset (clearing any command in progress) and the ACK function will be disabled. This is a change from previous BDM modules.



DBGC2 being logic 1 or logic 0, respectively. BDM requests have a higher priority than SWI requests. No data breakpoints are allowed in this mode.

TAGAB in DBGC2 selects whether the breakpoint mode is forced or tagged. The BKxMBH:L bits in DBGC3 select whether or not the breakpoint is matched exactly or is a range breakpoint. They also select whether the address is matched on the high byte, low byte, both bytes, and/or memory expansion. The RWx and RWxEN bits in DBGC3 select whether the type of bus cycle to match is a read, write, or read/write when performing forced breakpoints.

## 7.4.1.2 Full Breakpoint Mode

Full breakpoint mode requires a match on address and data for a breakpoint to occur. Upon a successful match, the system will enter background debug mode or initiate a software interrupt based upon the state of BDM in DBGC2 being logic 1 or logic 0, respectively. BDM requests have a higher priority than SWI requests. R/W matches are also allowed in this mode.

TAGAB in DBGC2 selects whether the breakpoint mode is forced or tagged. When TAGAB is set in DBGC2, only addresses are compared and data is ignored. The BKAMBH:L bits in DBGC3 select whether or not the breakpoint is matched exactly, is a range breakpoint, or is in page space. The BKBMBH:L bits in DBGC3 select whether the data is matched on the high byte, low byte, or both bytes. RWA and RWAEN bits in DBGC2 select whether the type of bus cycle to match is a read or a write when performing forced breakpoints. RWB and RWBEN bits in DBGC2 are not used in full breakpoint mode.

### NOTE

The full trigger mode is designed to be used for either a word access or a byte access, but not both at the same time. Confusing trigger operation (seemingly false triggers or no trigger) can occur if the trigger address occurs in the user program as both byte and word accesses.

## 7.4.1.3 Breakpoint Priority

Breakpoint operation is first determined by the state of the BDM module. If the BDM module is already active, meaning the CPU is executing out of BDM firmware, breakpoints are not allowed. In addition, while executing a BDM TRACE command, tagging into BDM is not allowed. If BDM is not active, the breakpoint will give priority to BDM requests over SWI requests. This condition applies to both forced and tagged breakpoints.

In all cases, BDM related breakpoints will have priority over those generated by the Breakpoint sub-block. This priority includes breakpoints enabled by the TAGLO and TAGHI external pins of the system that interface with the BDM directly and whose signal information passes through and is used by the breakpoint sub-block.



writes (0x0055 or 0x00AA) to the ARMCOP register must occur in the last 25% of the selected time-out period. A premature write the CRG will immediately generate a reset.

As soon as the reset sequence is completed the reset generator checks the reset condition. If no clock monitor failure is indicated and the latched state of the COP timeout is true, processing begins by fetching the COP vector.

## 9.5.3 Power-On Reset, Low Voltage Reset

The on-chip voltage regulator detects when  $V_{DD}$  to the MCU has reached a certain level and asserts poweron reset or low voltage reset or both. As soon as a power-on reset or low voltage reset is triggered the CRG performs a quality check on the incoming clock signal. As soon as clock quality check indicates a valid oscillator clock signal the reset sequence starts using the oscillator clock. If after 50 check windows the clock quality check indicated a non-valid oscillator clock the reset sequence starts using self-clock mode.

Figure 9-26 and Figure 9-27 show the power-up sequence for cases when the  $\overline{\text{RESET}}$  pin is tied to V<sub>DD</sub> and when the  $\overline{\text{RESET}}$  pin is held low.



Figure 9-26. RESET Pin Tied to V<sub>DD</sub> (by a Pull-Up Resistor)



Figure 9-27. RESET Pin Held Low Externally





Figure 10-26. Identifier Register 1 (IDR1) — Extended Identifier Mapping

### Table 10-25. IDR1 Register Field Descriptions — Extended

Field	Description
7:5 ID[20:18]	<b>Extended Format Identifier</b> — The identifiers consist of 29 bits (ID[28:0]) for the extended format. ID28 is the most significant bit and is transmitted first on the CAN bus during the arbitration procedure. The priority of an identifier is defined to be highest for the smallest binary number.
4 SRR	Substitute Remote Request — This fixed recessive bit is used only in extended format. It must be set to 1 by the user for transmission buffers and is stored as received on the CAN bus for receive buffers.
3 IDE	<ul> <li>ID Extended — This flag indicates whether the extended or standard identifier format is applied in this buffer. In the case of a receive buffer, the flag is set as received and indicates to the CPU how to process the buffer identifier registers. In the case of a transmit buffer, the flag indicates to the MSCAN what type of identifier to send.</li> <li>0 Standard format (11 bit)</li> <li>1 Extended format (29 bit)</li> </ul>
2:0 ID[17:15]	<b>Extended Format Identifier</b> — The identifiers consist of 29 bits (ID[28:0]) for the extended format. ID28 is the most significant bit and is transmitted first on the CAN bus during the arbitration procedure. The priority of an identifier is defined to be highest for the smallest binary number.

Module Base + 0x00X2



Figure 10-27. Identifier Register 2 (IDR2) — Extended Identifier Mapping

### Table 10-26. IDR2 Register Field Descriptions — Extended

Field	Description
7:0	Extended Format Identifier — The identifiers consist of 29 bits (ID[28:0]) for the extended format. ID28 is the
ID[14:7]	most significant bit and is transmitted first on the CAN bus during the arbitration procedure. The priority of an identifier is defined to be highest for the smallest binary number.



### Chapter 10 Freescale's Scalable Controller Area Network (S12MSCANV2)

If the bus clock is generated from a PLL, it is recommended to select the oscillator clock rather than the bus clock due to jitter considerations, especially at the faster CAN bus rates.

For microcontrollers without a clock and reset generator (CRG), CANCLK is driven from the crystal oscillator (oscillator clock).

A programmable prescaler generates the time quanta (Tq) clock from CANCLK. A time quantum is the atomic unit of time handled by the MSCAN.

Eqn. 10-2

# $Tq^{=} \frac{f_{CANCLK}}{(Prescaler value)}$

A bit time is subdivided into three segments as described in the Bosch CAN specification. (see Figure 10-43):

- SYNC\_SEG: This segment has a fixed length of one time quantum. Signal edges are expected to happen within this section.
- Time Segment 1: This segment includes the PROP\_SEG and the PHASE\_SEG1 of the CAN standard. It can be programmed by setting the parameter TSEG1 to consist of 4 to 16 time quanta.
- Time Segment 2: This segment represents the PHASE\_SEG2 of the CAN standard. It can be programmed by setting the TSEG2 parameter to be 2 to 8 time quanta long.

Eqn. 10-3



Figure 10-43. Segments within the Bit Time



## Chapter 12 Pulse-Width Modulator (PWM8B6CV1) Block Description

## 12.1 Introduction

The pulse width modulation (PWM) definition is based on the HC12 PWM definitions. The PWM8B6CV1 module contains the basic features from the HC11 with some of the enhancements incorporated on the HC12, that is center aligned output mode and four available clock sources. The PWM8B6CV1 module has six channels with independent control of left and center aligned outputs on each channel.

Each of the six PWM channels has a programmable period and duty cycle as well as a dedicated counter. A flexible clock select scheme allows a total of four different clock sources to be used with the counters. Each of the modulators can create independent continuous waveforms with software-selectable duty rates from 0% to 100%. The PWM outputs can be programmed as left aligned outputs or center aligned outputs

## 12.1.1 Features

- Six independent PWM channels with programmable period and duty cycle
- Dedicated counter for each PWM channel
- Programmable PWM enable/disable for each channel
- Software selection of PWM duty pulse polarity for each channel
- Period and duty cycle are double buffered. Change takes effect when the end of the effective period is reached (PWM counter reaches 0) or when the channel is disabled.
- Programmable center or left aligned outputs on individual channels
- Six 8-bit channel or three 16-bit channel PWM resolution
- Four clock sources (A, B, SA, and SB) provide for a wide range of frequencies.
- Programmable clock select logic
- Emergency shutdown

## 12.1.2 Modes of Operation

There is a software programmable option for low power consumption in wait mode that disables the input clock to the prescaler.

In freeze mode there is a software programmable option to disable the input clock to the prescaler. This is useful for emulation.



Chapter 16 Dual Output Voltage Regulator (VREG3V3V2) Block Description

## 16.1.3 Block Diagram

Figure 16-1 shows the function principle of VREG3V3V2 by means of a block diagram. The regulator core REG consists of two parallel sub-blocks, REG1 and REG2, providing two independent output voltages.



Figure 16-1. VREG3V3 Block Diagram



## 17.3.2.1 Flash Clock Divider Register (FCLKDIV)

The FCLKDIV register is used to control timed events in program and erase algorithms.





### Figure 17-4. Flash Clock Divider Register (FCLKDIV)

All bits in the FCLKDIV register are readable, bits 6–0 are write once and bit 7 is not writable.

### Table 17-3. FCLKDIV Field Descriptions

Field	Description
7 FDIVLD	<ul> <li>Clock Divider Loaded</li> <li>FCLKDIV register has not been written</li> <li>FCLKDIV register has been written to since the last reset</li> </ul>
6 PRDIV8	<ul> <li>Enable Prescalar by 8</li> <li>0 The oscillator clock is directly fed into the Flash clock divider</li> <li>1 The oscillator clock is divided by 8 before feeding into the Flash clock divider</li> </ul>
5–0 FDIV[5:0]	<b>Clock Divider Bits</b> — The combination of PRDIV8 and FDIV[5:0] must divide the oscillator clock down to a frequency of 150 kHz – 200 kHz. The maximum divide ratio is 512. Refer to Section 17.4.1.1, "Writing the FCLKDIV Register" for more information.

## 17.3.2.2 Flash Security Register (FSEC)

The FSEC register holds all bits associated with the security of the MCU and Flash module.

Module Base + 0x0001



### Figure 17-5. Flash Security Register (FSEC)

All bits in the FSEC register are readable but not writable.

The FSEC register is loaded from the Flash configuration field at 0xFF0F during the reset sequence, indicated by F in Figure 17-5.



## 17.4.1.4 Illegal Flash Operations

### 17.4.1.4.1 Access Error

The ACCERR flag in the FSTAT register will be set during the command write sequence if any of the following illegal Flash operations are performed causing the command write sequence to immediately abort:

- 1. Writing to the Flash address space before initializing the FCLKDIV register
- 2. Writing a misaligned word or a byte to the valid Flash address space
- 3. Writing to the Flash address space while CBEIF is not set
- 4. Writing a second word to the Flash address space before executing a program or erase command on the previously written word
- 5. Writing to any Flash register other than FCMD after writing a word to the Flash address space
- 6. Writing a second command to the FCMD register before executing the previously written command
- 7. Writing an invalid command to the FCMD register
- 8. Writing to any Flash register other than FSTAT (to clear CBEIF) after writing to the FCMD register
- 9. The part enters stop mode and a program or erase command is in progress. The command is aborted and any pending command is killed
- 10. When security is enabled, a command other than mass erase originating from a non-secure memory or from the background debug mode is written to the FCMD register
- 11. A 0 is written to the CBEIF bit in the FSTAT register to abort a command write sequence.

The ACCERR flag will not be set if any Flash register is read during the command write sequence. If the Flash array is read during execution of an algorithm (CCIF=0), the Flash module will return invalid data and the ACCERR flag will not be set. If an ACCERR flag is set in the FSTAT register, the Flash command controller is locked. It is not possible to launch another command until the ACCERR flag is cleared.

### 17.4.1.4.2 Protection Violation

The PVIOL flag in the FSTAT register will be set during the command write sequence after the word write to the Flash address space if any of the following illegal Flash operations are performed, causing the command write sequence to immediately abort:

- 1. Writing a Flash address to program in a protected area of the Flash array (see Section 17.3.2.5).
- 2. Writing a Flash address to erase in a protected area of the Flash array.
- 3. Writing the mass erase command to the FCMD register while any protection is enabled.

If the PVIOL flag is set, the Flash command controller is locked. It is not possible to launch another command until the PVIOL flag is cleared.



Chapter 19 64 Kbyte Flash Module (S12FTS64KV4)





Figure 19-4. Flash Memory Map





Figure 19-25. Example Erase Verify Command Flow



Chapter 20 96 Kbyte Flash Module (S12FTS96KV1)

## 20.1.3 Modes of Operation

See Section 20.4.2, "Operating Modes" for a description of the Flash module operating modes. For program and erase operations, refer to Section 20.4.1, "Flash Command Operations".

## 20.1.4 Block Diagram

Figure 20-1Figure 20-2 shows a block diagram of the FTS128K1FTS96K module.







Chapter 20 96 Kbyte Flash Module (S12FTS96KV1)



Note: 0x38–0x3F correspond to the PPAGE register content

Figure 20-3. Flash Memory Map



injection current may flow out of  $V_{DD5}$  and could result in external power supply going out of regulation. Insure external  $V_{DD5}$  load will shunt current greater than maximum injection current. This will be the greatest risk when the MCU is not consuming power; e.g. if no system clock is present, or if clock rate is very low which would reduce overall power consumption.

## A.1.5 Absolute Maximum Ratings

Absolute maximum ratings are stress ratings only. A functional operation under or outside those maxima is not guaranteed. Stress beyond those limits may affect the reliability or cause permanent damage of the device.

This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (e.g., either  $V_{SS5}$  or  $V_{DD5}$ ).

Num	Rating	Symbol	Min	Max	Unit
1	I/O, Regulator and Analog Supply Voltage	V <sub>DD5</sub>	-0.3	6.5	V
2	Digital Logic Supply Voltage <sup>(1)</sup>	V <sub>DD</sub>	-0.3	3.0	V
3	PLL Supply Voltage <sup>1</sup>	V <sub>DDPLL</sub>	-0.3	3.0	V
4	Voltage difference $V_{DDX}$ to $V_{DDR}$ and $V_{DDA}$	$\Delta_{VDDX}$	-0.3	0.3	V
5	Voltage difference $V_{SSX}$ to $V_{SSR}$ and $V_{SSA}$	$\Delta_{VSSX}$	-0.3	0.3	V
6	Digital I/O Input Voltage	V <sub>IN</sub>	-0.3	6.5	V
7	Analog Reference	V <sub>RH,</sub> V <sub>RL</sub>	-0.3	6.5	V
8	XFC, EXTAL, XTAL inputs	V <sub>ILV</sub>	-0.3	3.0	V
9	TEST input	V <sub>TEST</sub>	-0.3	10.0	V
10	Instantaneous Maximum Current Single pin limit for all digital I/O pins <sup>(2)</sup>	Ι <sub>D</sub>	-25	+25	mA
11	Instantaneous Maximum Current Single pin limit for XFC, EXTAL, XTAL <sup>(3)</sup>	I <sub>DL</sub>	-25	+25	mA
12	Instantaneous Maximum Current Single pin limit for TEST <sup>(4)</sup>	I <sub>DT</sub>	-0.25	0	mA
13	Operating Temperature Range (packaged)	T <sub>A</sub>	- 40	125	°C
14	Operating Temperature Range (junction)	TJ	- 40	140	°C
15	Storage Temperature Range	T <sub>stg</sub>	- 65	155	°C

### Table A-1. Absolute Maximum Ratings

1. The device contains an internal voltage regulator to generate the logic and PLL supply out of the I/O supply. The absolute maximum ratings apply when the device is powered from an external source.

2. All digital I/O pins are internally clamped to  $V_{SSX}$  and  $V_{DDX}$ ,  $V_{SSR}$  and  $V_{DDR}$  or  $V_{SSA}$  and  $V_{DDA}$ .

3. These pins are internally clamped to  $V_{\mbox{\scriptsize SSPLL}}$  and  $V_{\mbox{\scriptsize DDPLL}}$ 

4. This pin is clamped low to V<sub>SSX</sub>, but not clamped high. This pin must be tied low in applications.



Num	С	Rating	Symbol	Min	Тур	Max	Unit
1	Т	Thermal Resistance LQFP48, single layer PCB <sup>(2)</sup>	θ <sub>JA</sub>	_	_	69	°C/W
2	т	Thermal Resistance LQFP48, double sided PCB with 2 internal planes <sup>(3)</sup>	θ <sub>JA</sub>	_	_	53	°C/W
3	Т	Junction to Board LQFP48	θ <sub>JB</sub>	_	_	30	°C/W
4	Т	Junction to Case LQFP48	θ <sub>JC</sub>	—	_	20	°C/W
5	Т	Junction to Package Top LQFP48	Ψ <sub>JT</sub>	—	_	4	°C/W
6	Т	Thermal Resistance LQFP52, single sided PCB	θ <sub>JA</sub>	_	_	65	°C/W
7	т	Thermal Resistance LQFP52, double sided PCB with 2 internal planes	θ <sub>JA</sub>	_	_	49	°C/W
8	Т	Junction to Board LQFP52	θ <sub>JB</sub>	_	_	31	°C/W
9	Т	Junction to Case LQFP52	θ <sub>JC</sub>	_	_	17	°C/W
10	Т	Junction to Package Top LQFP52	Ψ <sub>JT</sub>	_	_	3	°C/W
11	Т	Thermal Resistance QFP 80, single sided PCB	θ <sub>JA</sub>	_	_	52	°C/W
12	т	Thermal Resistance QFP 80, double sided PCB with 2 internal planes	θ <sub>JA</sub>	_	_	42	°C/W
13	Т	Junction to Board QFP80	θ <sub>JB</sub>	_	_	28	°C/W
14	Т	Junction to Case QFP80	θ <sub>JC</sub>	_		18	°C/W
15	Т	Junction to Package Top QFP80	Ψ <sub>JT</sub>	_		4	°C/W

1. The values for thermal resistance are achieved by package simulations

2. PC Board according to EIA/JEDEC Standard 51-2

3. PC Board according to EIA/JEDEC Standard 51-7



In Figure A-9 the timing diagram for slave mode with transmission format CPHA=1 is depicted.

### Figure A-9. SPI Slave Timing (CPHA=1)

In Table A-22 the timing characteristics for slave mode are listed.

Num	С	Characteristic	Symbol	Min	Тур	Max	Unit
1	D	SCK Frequency	f <sub>sck</sub>	DC	—	1/4	f <sub>bus</sub>
1	Р	SCK Period	t <sub>sck</sub>	4	_	∞	t <sub>bus</sub>
2	D	Enable Lead Time	t <sub>lead</sub>	4	_	—	t <sub>bus</sub>
3	D	Enable Lag Time	t <sub>lag</sub>	4	—	—	t <sub>bus</sub>
4	D	Clock (SCK) High or Low Time	t <sub>wsck</sub>	4	—	—	t <sub>bus</sub>
5	D	Data Setup Time (Inputs)	t <sub>su</sub>	8	_	—	ns
6	D	Data Hold Time (Inputs)	t <sub>hi</sub>	8	—	—	ns
7	D	Slave Access Time (time to data active)	t <sub>a</sub>	—	—	20	ns
8	D	Slave MISO Disable Time	t <sub>dis</sub>	—	—	22	ns
9	D	Data Valid after SCK Edge	t <sub>vsck</sub>	_		$30 + t_{bus}$	ns
10	D	Data Valid after SS fall	t <sub>vss</sub>	—	—	30 + t <sub>bus</sub> 1	ns
11	D	Data Hold Time (Outputs)	t <sub>ho</sub>	20	—	—	ns
12	D	Rise and Fall Time Inputs	t <sub>rfi</sub>	—	_	8	ns
13	D	Rise and Fall Time Outputs	t <sub>rfo</sub>	_	_	8	ns

Table A-22. SPI Slave Mode Timing Characteristics

1. t<sub>bus</sub> added due to internal synchronization delay